

Delivering 100 Gbps Solutions for Chip-to-Module and Direct Attach Copper (DAC) Cable Implementations

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Presentation Outline

- Introduction
- Skew Impact on S_{dd21} & S_{cd21}
- Mating Zone Reflections
- Measured results of 112 Gbps DAC
 - Impact of skew and reflections
- Measured results of 112 Gbps C2M
 - Impact of skew and reflections
- Conclusion







Skew Impact on *S*_{dd21} & *S*_{cd21}

$$S_{dd21} = \frac{|S_{21}|e^{j\theta_{21}} + |S_{43}|e^{j\theta_{43}} - |S_{41}|e^{j\theta_{41}} - |S_{23}|e^{j\theta_{23}}}{2}$$

$$S_{dd21} = |IL| \cos\left(\frac{\Delta\theta}{2}\right) e^{j\theta_{21}} - |X| \cos\left(\frac{\Delta\theta_X}{2}\right) e^{j\theta_{41}}$$

$$S_{cd21} = \frac{|S_{21}|e^{j\theta_{21}} - |S_{43}|e^{j\theta_{43}} + |S_{41}|e^{j\theta_{41}} - |S_{23}|e^{j\theta_{23}}}{2}$$

$$S_{cd21} = |IL| \left[-jsin\left(\frac{\Delta\theta}{2}\right) \right] e^{j\theta_{21}} + |X| \left[-jsin\left(\frac{\Delta\theta_X}{2}\right) \right] e^{j\theta_{41}}$$

- S_{dd21} is modified by cosine function
- S_{cd21} is modified by sine function
- Higher frequencies impacted more than lower frequencies as skew increases
- Skew impacts 112 Gbps channels more than 56 Gbps channels



freq, GHz





Mating Zone Impedance (Mating Zone Reflections)



- OSFP, lowest pad width-to-pitch ratio = 0.63
- 2D field solver used to calculate characteristic impedance of ONLY the mating pads acting as microstrip traces
- 10% reduction in pad width b/w QSFP28 & QSFP-DD
 - Yields 10 ohm improvement



Form Factor	Impedance (Ohms)
QSFP28	82
QSFP-DD	92
OSFP	101



Mating Zone Impedance (Mating Zone Reflections)

Form Factor	Modeled Z _o without Rcpt (Ω)	Measured Z _{diff} with Rcpt (Ω)	Δ
QSFP28	82	72	10
QSFP-DD	92	77	15
OSFP	101	86	15

- Largest impact on mating interface impedance comes from contact lead-in and PCB pad stub from contact wipe





-OSFP - •QSFP-DD •••• QSFP28



Mating Zone Impedance (Mating Zone Reflections)



56 Gbps OSFP connector modified by reducing

contact lead-in (referred to as 112 Gbps

-





Impact of Skew & Reflections, OSFP 112 Gbps DAC, Test Set-up







Impact of Skew & Reflections, OSFP 112 Gbps DAC, Measurement Results



- Measurement results shown for
 - 1.0m 30 AWG Tx8 lane
 - 1.5m 28 AWG Tx8 lane
- 112 Gbps connector improves differential insertion loss at higher frequencies
- Test fixture skew included in measurement results



Measured Channel w/ 30 Gops Conn (Blue) Measured Channel w/ 112 Gbps Conn (Red)

Impact of Skew & Reflections, OSFP 112 Gbps DAC



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- COM calculated using Version 2.51 COM script developed for IEEE 802.3ck specification
- Results for 32 lanes (Tx7 & Tx8 lanes/30 & 28 AWG/ 56 & 112 Gbps Connector/ 0, 3, 6, and 9 ps added skew)
- All instances pass COM Case 1 (shorter package length)
- Failures for COM Case 2, 56 Gbps conn w/ 9 ps of skew & 2 instances of 112 Gbps conn w/ 9 ps of skew
- Channels with increased differential insertion loss exhibit lower COM value
- Minimizing mating zone reflections made channels more tolerant of skew





Impact of Skew & Reflections, 112G VSR (C2M) Channel



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Impact of Skew & Reflections, 112G VSR (C2M), COM Calculation COM Case 2 COM Case 1 5 5 4.5 4.5 ٠ 0 \diamond 4 COM Value(dB) COM Value(dB) ٠ 3.5 3.5 \diamond 3 3 2.5 2.5 2 2 -23 -22 -21 -20 -19 -18 -17 -16 -15 -23 -22 -19 -21 -18 -17 -20 -16 -15 Loss at 26.56 GHz Loss at 26.56 GHz 🔺 <3ps 112G Conn 🗧 3ps 112G Conn 🔹 6ps 112G Conn 💿 9ps 112G Conn 🛆 <3ps 56G Conn ▲ <3ps 112G Conn = 3ps 112G Conn ◆ 6ps 112G Conn ● 9ps 112G Conn △ <3ps 56G Conn □ 3ps 56G Conn ◇ 6ps 56G Conn O 9ps 56G Conn —Limit 3ps 56G Conn O 9ps 56G Conn —Limit 6p 56G Conn

- COM calculated using Version 2.41 COM script developed for IEEE 802.3ck specification
- Results for 8 lanes (56 & 112 Gbps Connector/ 0, 3, 6, and 9 ps added skew)
- All instances pass COM Case 1 & COM Case 2
- Unlike DAC channel, C2M does not exhibit differential insertion loss sensitivity



Conclusions

- Two main drivers in extending reach are skew and mating zone reflections
- Skew, differential insertion loss, and mode conversion are interrelated
- By minimizing skew, less differential energy is converted to common mode energy, and differential throughput can be maximized
- For any degree of skew one can relate the change in differential insertion loss to the change in mode conversion
- It was only when skew was added to the DAC channel that failures started to occur because of the increased differential insertion loss
- If mating zone reflections can be minimized, a channel can be more tolerant of skew from a differential insertion loss standpoint
- Minimizing both skew and mating zone reflections are strong drivers in being able to maximize channel reach for 112G.



References

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